

# Spring-loaded test probe

## GKS-075 217 120 A 2000 LH

Item GKS-075-0779



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Partner for Future Technology

- Well-established test probes for contacting PCBs
- For optimal contact to the test points (e.g. pads, vias, and pins), various tip styles with various diameters and finishes are available.
- Various spring forces available as well as versions with stainless steel springs suitable for high temperatures
- Used for setting the optimum stroke conditions in the test fixture, various installation heights can be achieved by combining test probes and receptacles

### General data

Product group	ICT / FCT (in-circuit test and function test)
Sub-product group	Standard stroke test probe
Series	GKS-075 LH long version
Grid	1.91 mm [75 mil]
Contacting from	Pad, Via, Female connector
Magnetic	Yes
Installation type	Plug-in
Quick-exchange system	Yes
Adjustable installation height	No
Non-rotating	No
Compatible receptacle(s)	KS-075
Min. temperature	- 40 °C [- 104 °F]
Max. temperature	+ 80 °C [+ 176 °F]
RoHS-compliant	RoHS-3;6a

### Electrical data

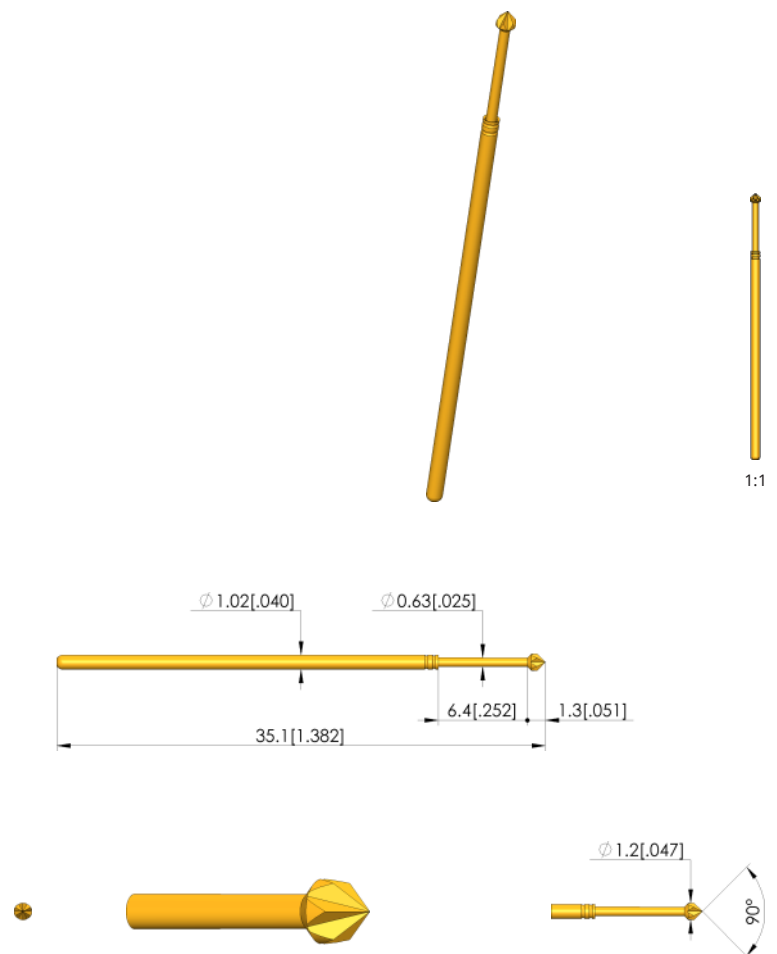
Current load capacity / rated current	3 A
Typical resistance (Ri)	<20 mOhm

### Mechanical data

Total length	35.1 mm [1.38 in]
Barrel diameter	1.02 mm [.040 in]
Maximum stroke	6.35 mm [.25 in]
Spring pre-load	0.85 N [3.05 ozf]
Collar height	00
Spring force at working stroke	2 N [7.19 ozf]
Recommended working stroke	4.3 mm [.169 in]

### Tip style data

Tip style	17 hexagonal pyramid with cutting edges, self-cleaning
Tip diameter	1.2 mm [.047 in]
Tip style surface	A gold
Tip style material	2 steel



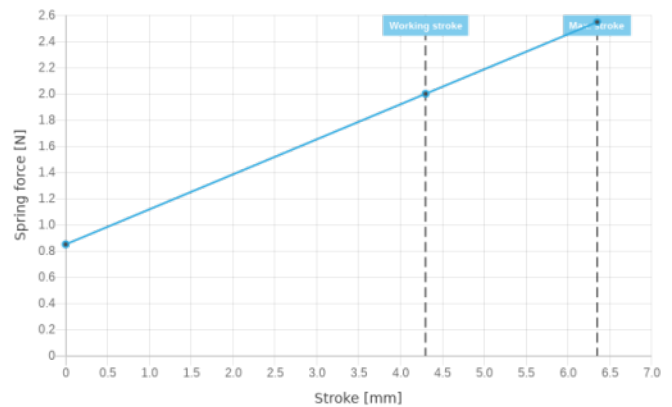
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Prices and delivery times on request.  
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Learn more about  
ICT/FCT Test probes

